What is claimed is:

1. A machine-readable medium having a set of machine-readable instructions for causing a computer to perform a method comprising:

checking a layout having a layout line width for at least one line versus a schematic having a schematic line width for the at least one line;

extracting a line width property from the schematic;

transferring the line width property to the layout; and

checking a design for the at least one line versus the schematic.

2. The machine-readable medium of claim 1, wherein the method further comprises associating line width markers with their respective lines in a layout database.

3. The machine-readable medium of claim 1, wherein, in the method, checking the design for the at least one line versus the schematic comprises checking the line width property for the at least one line versus a design line width.

4. The machine-readable medium of claim 1, wherein the method further comprises excluding from checking the design in areas near or above a transistor.

5. The machine-readable medium of claim 1, wherein the method further comprises generating an error condition when a design line width is less than the line width property for the at least one line.

6. The machine-readable medium of claim 1, wherein the method further comprises associating, element by element, an object in the schematic with a related object in the layout.

7. The machine-readable medium of claim 1, wherein the method further comprises uniquely identifying every line in the schematic with a corresponding line in the layout.

8. The machine-readable medium of claim 1, wherein, in the method, transferring the line width property to the layout is performed when the schematic matches the layout.

9. A machine-readable medium having a set of machine-readable instructions for causing a computer to perform a method comprising:

determining whether a schematic matches a layout, the schematic having a plurality of schematic lines, each of the schematic lines having a line width marker;

transferring a line width property for each line width marker from the schematic to the layout when the schematic matches the layout; and

checking design line widths versus corresponding line width properties transferred to the layout.

10. The machine-readable medium of claim 9, wherein the method further comprises generating an error condition when a design line width is less than a corresponding line width property.

11. The machine-readable medium of claim 9, wherein, in the method, the layout contains each line width marker.

12. The machine-readable medium of claim 9, wherein, in the method, the layout contains each line width marker in a line width layer of the layout.

13. The machine-readable medium of claim 9, wherein, in the method, when the schematic matches the layout, every schematic line in the schematic is uniquely identified with a corresponding line in the layout.

14. The machine-readable medium of claim 9, wherein the method further comprises associating the line width markers with their respective lines in a layout database.

15. A machine-readable medium having a set of machine-readable instructions for causing a computer to perform a method comprising:

verifying that each of a plurality of lines in a schematic is uniquely identified with its corresponding line in a layout, at least one of the lines in the schematic having a line width marker;

extracting a line width property of the line width marker from the schematic;

transferring the line width property to the layout; and

checking the line width property versus a corresponding design line width.

16. The machine-readable medium of claim 15, wherein the method further comprises associating the line width marker with its respective line in a layout database.

17. The machine-readable medium of claim 15, wherein the method further comprises generating an error condition when the design line width is less than the corresponding line width property.

18. The machine-readable medium of claim 15, wherein, in the method, the layout contains the line width marker.

19. The machine-readable medium of claim 15, wherein the method further comprises excluding from checking the design in areas near or above a transistor.